



ALPHA & OMEGA
SEMICONDUCTOR

AO4705

**P-Channel Enhancement Mode Field Effect Transistor
with Schottky Diode**



General Description

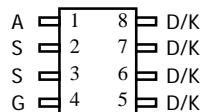
The AO4705 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. A Schottky diode is provided to facilitate the implementation of non-synchronous DC-DC converters. Standard Product AO4705 is Pb-free (meets ROHS & Sony 259 specifications). AO4705 is a Green Product ordering option. AO4705 and AO4705L are electrically identical.

Features

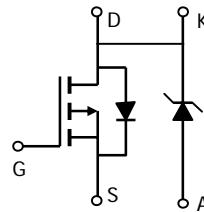
V_{DS} (V) = -30V
 I_D = -10A (V_{GS} = -10V)
 $R_{DS(ON)} < 14m\Omega$ (V_{GS} = -20V)
 $R_{DS(ON)} < 16m\Omega$ (V_{GS} = -10V)

SCHOTTKY

V_{DS} (V) = 30V, I_F = 5A, $V_F < 0.52V @ 3A$



SOIC-8



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	MOSFET	Schottky	Units
Drain-Source Voltage	V_{DS}	-30		V
Gate-Source Voltage	V_{GS}	± 25		V
Continuous Drain Current ^A	I_D	-10		A
		-8		
Pulsed Drain Current ^B	I_{DM}	-60		
Schottky reverse voltage	V_{KA}		30	V
Continuous Forward Current ^A	I_F		5	A
			3.5	
Pulsed Forward Current ^B	I_{FM}		30	
Power Dissipation	P_D	3	3	W
		2	2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	°C

Parameter: Thermal Characteristics MOSFET	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	28	40	°C/W
Maximum Junction-to-Ambient ^A		54	75	
Maximum Junction-to-Lead ^C		21	30	
Thermal Characteristics Schottky				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	36	40	°C/W
Maximum Junction-to-Ambient ^A		67	75	
Maximum Junction-to-Lead ^C		25	30	

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.7	-2.5	-3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	60			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-10\text{A}$ $T_J=125^\circ\text{C}$		13	16	$\text{m}\Omega$
		$V_{GS}=-20\text{V}, I_D=-10\text{A}$		16	21	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-10\text{A}$		25		$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-10\text{A}$		26		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.72	-1	V
I_S	Maximum Body-Diode Continuous Current				-4.2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		2076		pF
C_{oss}	Output Capacitance			503		pF
C_{rss}	Reverse Transfer Capacitance			302		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2		Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-10\text{A}$		37.2		nC
Q_{gs}	Gate Source Charge			7		nC
Q_{gd}	Gate Drain Charge			10.4		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=1.0\Omega, R_{\text{GEN}}=3\Omega$		12.4		ns
t_r	Turn-On Rise Time			8.2		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			25.6		ns
t_f	Turn-Off Fall Time			12		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-10\text{A}, dI/dt=100\text{A}/\mu\text{s}$		33		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-10\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23		nC
SCHOTTKY PARAMETERS						
V_F	Forward Voltage Drop	$I_F=3.0\text{A}$		0.48	0.52	V
I_{rm}	Maximum reverse leakage current	$V_R=24\text{V}$		0.07	0.15	mA
		$V_R=24\text{V}, T_J=125^\circ\text{C}$		4.2	20	
		$V_R=24\text{V}, T_J=150^\circ\text{C}$		15	60	
C_T	Junction Capacitance	$V_R=15\text{V}$		120		pF

A: The value of R_{QA} is measured with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{QA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6, 12, 14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

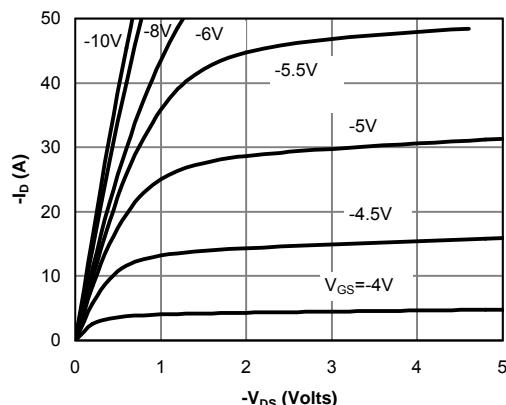


Fig 1: On-Region Characteristics

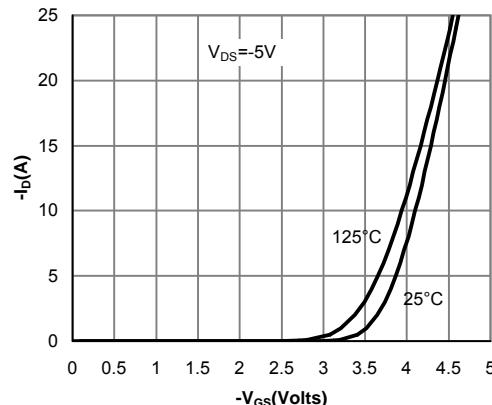


Figure 2: Transfer Characteristics

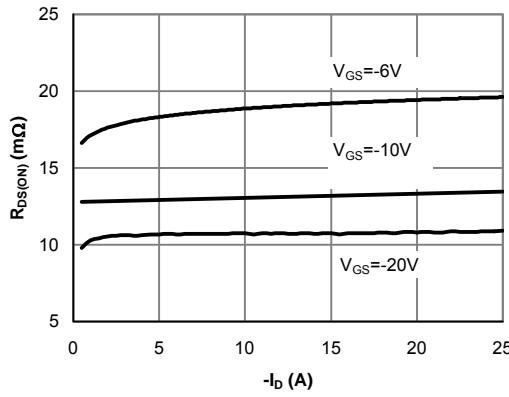


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

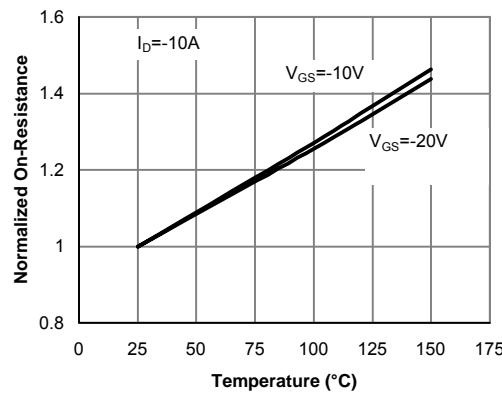


Figure 4: On-Resistance vs. Junction Temperature

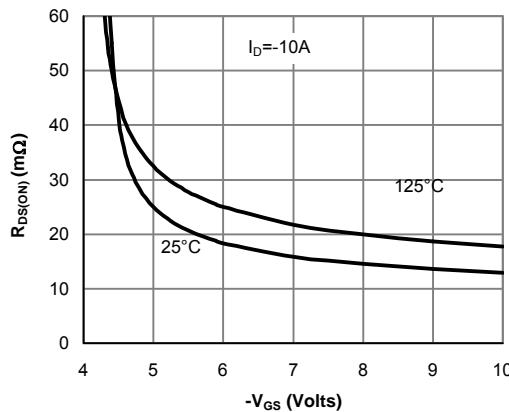


Figure 5: On-Resistance vs. Gate-Source Voltage

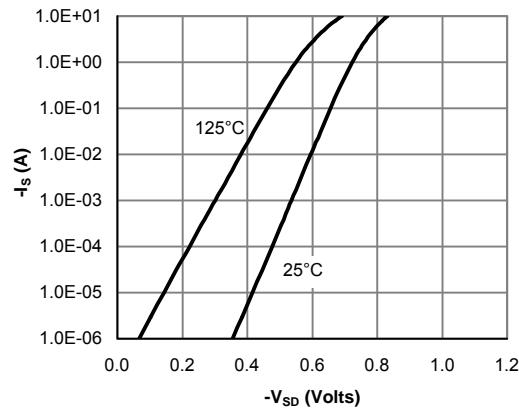


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

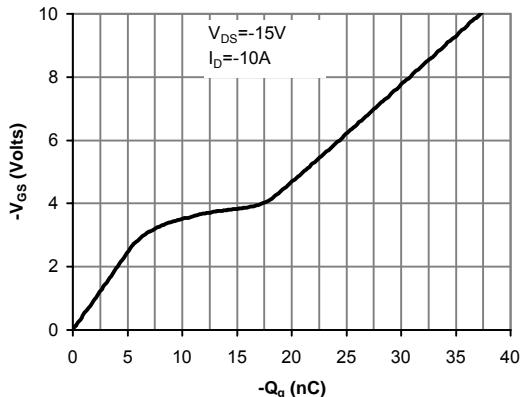


Figure 7: Gate-Charge Characteristics

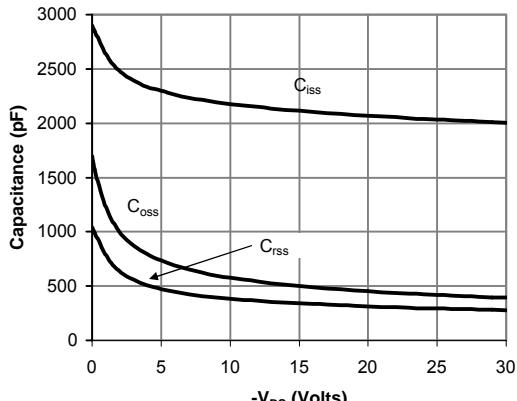


Figure 8: Capacitance Characteristics

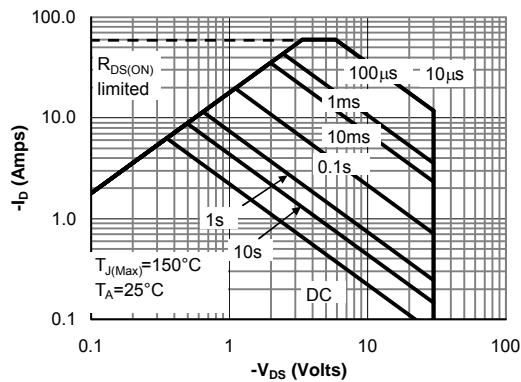


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

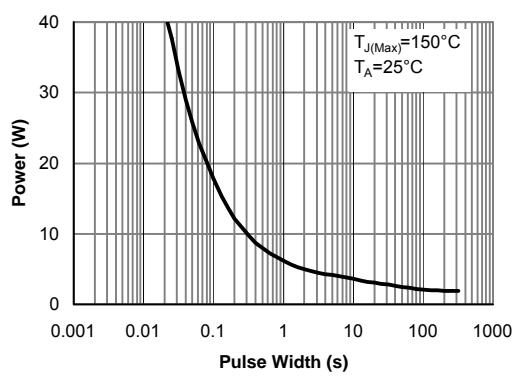


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

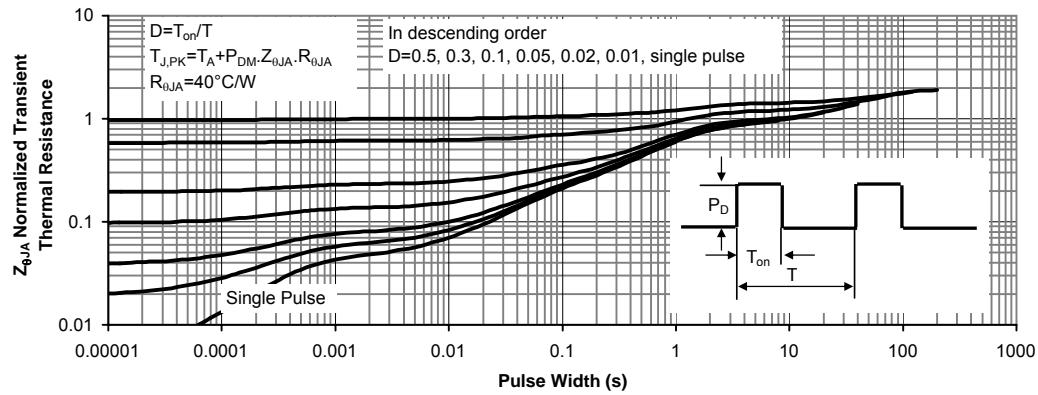


Figure 11: Normalized Maximum Transient Thermal Impedance

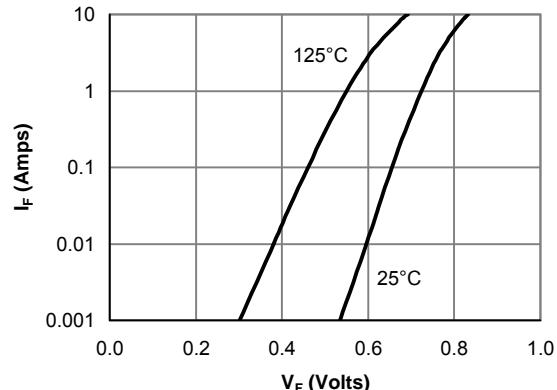
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: SCHOTTKY


Figure 12: Schottky Forward Characteristics

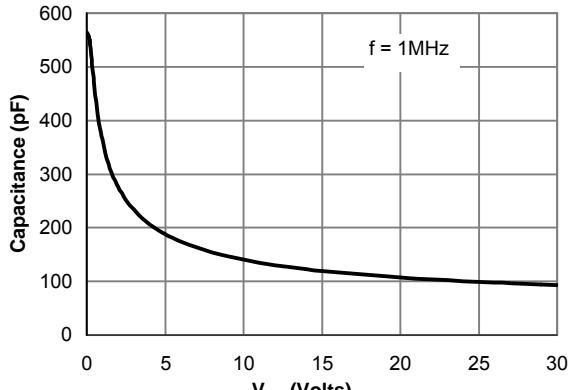


Figure 13: Schottky Capacitance Characteristics

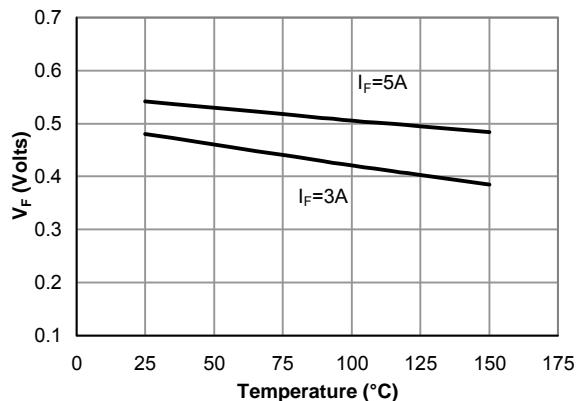


Figure 14: Schottky Forward Drop vs. Junction Temperature

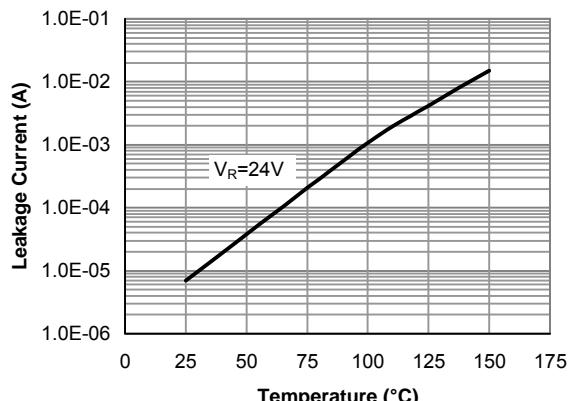


Figure 15: Schottky Leakage Current vs. Junction Temperature

